

SLOVENSKI STANDARD SIST EN IEC 62884-4:2019

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Merilne tehnike za piezoelektrične, dielektrične in elektrostatične oscilatorje - 4. del: Preskusne metode kratkotrajne frekvenčne stabilnosti (IEC 62884-4:2019)

Measurement techniques of piezoelectric, dielectric and electrostatic oscillators - Part 4 : Short-term frequency stability test methods (IEC 62884-4:2019)

Messverfahren für piezoelektrische, dielektrische und elektrostatische Oszillatoren – Teil 4: Prüfverfahren für die Kurzzeit-Frequenzstabilität (IEC 62884-4:2019)

Techniques de mesure des oscillateurs piezoelectriques, diélectriques et électrostatiques - Partie 4: Méthodes d'essai de stabilité à court-terme de la fréquence (IEC 62884-4:2019) SIST EN IEC 62884-4:2019 https://standards.iteh.ai/catalog/standards/sist/34fl dea3-93ce-4be4-b61e-

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Measurement techniques of piezoelectric, dielectric and electrostatic oscillators - Part 4 : Short-term frequency stability test methods
(IEC 62884-4:2019)

Techniques de mesure des oscillateurs piézoélectriques, diélectriques et électrostatiques - Partie 4: Méthodes d'essai de stabilité à court-terme de la fréquence (IEC 62884-4:2019) Messverfahren für piezoelektrische, dielektrische und elektrostatische Oszillatoren - Teil 4: Prüfverfahren für die Kurzzeit-Frequenzstabilität (IEC 62884-4:2019)

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European Committee for Electrotechnical Standardization Comité Européen de Normalisation Electrotechnique Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

EN IEC 62884-4:2019 (E)

European foreword

The text of document 49/1277/CDV, future edition 1 of IEC 62884-4, prepared by IEC/TC 49 "Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 62884-4:2019.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2022-06-10

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In the official version, for Bibliography, the following note has to be added for the standard indicated:

IEC 60068-1 NOTE Harmonized as EN 60068-1

EN IEC 62884-4:2019 (E)

Annex ZA

(normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	EN/HD	<u>Year</u>
IEC 60027	series	Letters symbols to be used in electrical technology - Part 1: General	-	series
IEC 60050-561	-	International Electrotechnical Vocabulary - Part 561: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection	-	-
IEC 60469	-	Transitions, pulses and related waveforms - Terms, definitions and algorithms	EN 60469	-
IEC 60617	- iT	Standard data element types with associated classification scheme for electric components Part 4: IEC reference collection fo standard data element types and component classes	-	-
IEC 60679-1	- https://s	Piezoelectric, dielectric and electrostatic oscillators of assessed quality Part 1: Generic tangent licetal catalog standards/ssty34f1 dea3-93ce-4be4-b610 specification 18da8/sist-en-iec-62884-4-2019	EN 60679-1	-
IEC 62884-1	-	Measurement techniques of piezoelectric, dielectric and electrostatic oscillators - Part 1: Basic methods for the measurement	EN 62884-1	-
ISO 80000-1	-	Quantities and units Part 1: General	EN ISO 80000-1	-

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Measurement techniques of piezoelectric, dielectric and electrostatic oscillators – Part 4: Short-term frequency stability test methods

Techniques de mesure des oscillateurs piézoélectriques, diélectriques et électrostatiques standards.iteh.ai/catalog/standards/sist/34fl dea3-93ce-4be4-b61e-Partie 4: Méthodes d'essaï de stabilité à coûtteme de la fréquence

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

MEASUREMENT TECHNIQUES OF PIEZOELECTRIC, DIELECTRIC AND ELECTROSTATIC OSCILLATORS –

Part 4: Short-term frequency stability test methods

FOREWORD

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International Standard IEC 62884-4 has been prepared by IEC technical committee 49: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection.

The text of this International Standard is based on the following documents:

CDV	Report on voting
49/1277/CDV	49/1292/RVC

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

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A list of all parts in the IEC 62884 series, published under the general title *Measurement techniques of piezoelectric, dielectric and electrostatic oscillators*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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MEASUREMENT TECHNIQUES OF PIEZOELECTRIC, DIELECTRIC AND ELECTROSTATIC OSCILLATORS –

Part 4: Short-term frequency stability test methods

1 Scope

This part of IEC 62884 describes the methods for the measurement and evaluation of the short-term frequency stability tests of piezoelectric, dielectric and electrostatic oscillators. Its purpose is to unify the test and evaluation methods for short-term frequency stability.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027 (all parts), Letter symbols to be used in electrical technology

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IEC 60050-561, International electrotechnical vocabulary – Part 561: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection. Available at www.electropedia.org

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IEC 60469, Transitions//pulses and related waveforms 441 Terms, définitions and algorithms 7ba2cd518da8/sist-en-iec-62884-4-2019

IEC 60617, Graphical symbols for diagrams, available at http://std.iec.ch/iec60617

IEC 60679-1, Piezoelectric, dielectric and electrostatic oscillators of assessed qualify – Part 1: Generic specification

IEC 62884-1, Measurement techniques of piezoelectric, dielectric and electrostatic oscillators – Part 1: Basic methods for the measurement

ISO 80000-1, Quantities and units – Part 1: General

3 Terms and definitions, units and symbols

3.1 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 60679-1 apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses.

- IEC Electropedia: available at http://www.electropedia.org
- ISO Online browsing platform: available at http://www.iso.org/obp

3.2 Units and symbols

Units, graphical symbols, letter symbols and terminology shall, wherever possible, be taken from the following standards: